

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under  
Reexamination  
FERLITSCH, ANDREW R.

Examiner

CHAN S. PARK

Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-2003/0053118	03-2003	Muramoto et al.	358/1.15
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